

N and P Channel Enhancement Mode Power MOSFET

Description

The 6706A uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge. It can be used in a wide variety of applications.

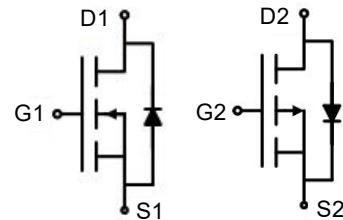
General Features

- NMOS
 - V_{DS} 30V
 - I_D (at $V_{GS} = 10V$) 6.5A
 - $R_{DS(ON)}$ (at $V_{GS} = 10V$) < 20mΩ
 - $R_{DS(ON)}$ (at $V_{GS} = 4.5V$) < 30mΩ
- 100% Avalanche Tested
- RoHS Compliant

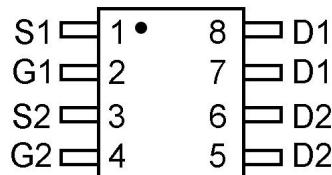
- PMOS
 - V_{DS} -30V
 - I_D (at $V_{GS} = -10V$) -5A
 - $R_{DS(ON)}$ (at $V_{GS} = -10V$) < 45mΩ
 - $R_{DS(ON)}$ (at $V_{GS} = -4.5V$) < 70mΩ
- 100% Avalanche Tested
- RoHS Compliant

Application

- Power switch
- DC/DC converters



Schematic diagram



pin assignment



SOP-8

Ordering Information

Device	Package	Marking	Packaging
6706A	SOP-8 Dual	6706	4000pcs/Reel

Absolute Maximum Ratings $T_C = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	NMOS	PMOS	Unit
Drain-Source Voltage	V_{DS}	30	-30	V
Continuous Drain Current	I_D	6.5	-5	A
Pulsed Drain Current (note1)	I_{DM}	26	-20	A
Gate-Source Voltage	V_{GS}	± 20	± 20	V
Power Dissipation	P_D	2.0	2.0	W
Single pulse avalanche energy (note2)	E_{AS}	9	10	mJ
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 To 150	-55 To 150	°C

Thermal Resistance

Parameter	Symbol	NMOS	PMOS	Unit
Thermal Resistance, Junction-to-Ambient	R_{thJA}	62.5	62.5	°C/W

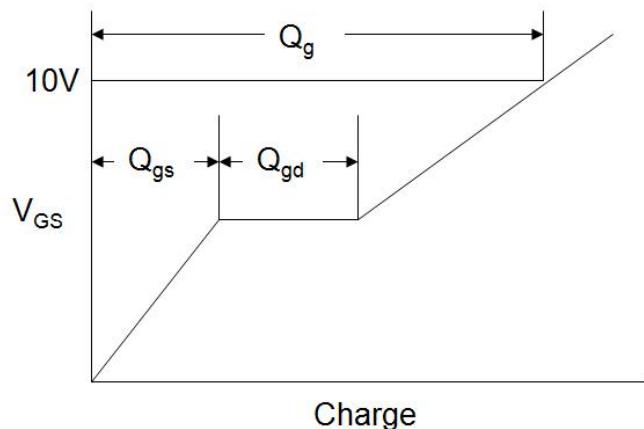
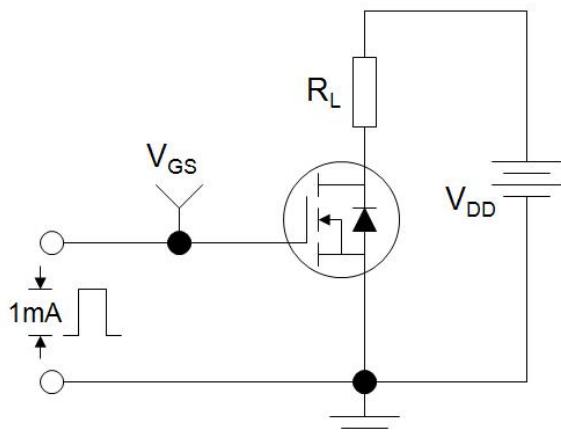
NMOS Specifications $T_J = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
Static Parameters						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	30	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 30\text{V}, V_{\text{GS}} = 0\text{V}$	--	--	1	μA
Gate-Source Leakage	I_{GSS}	$V_{\text{GS}} = \pm 20\text{V}$	--	--	± 100	nA
Gate-Source Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1	1.5	2	V
Drain-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_D = 5\text{A}$	--	16	20	$\text{m}\Omega$
		$V_{\text{GS}} = 4.5\text{V}, I_D = 5\text{A}$	--	23	30	
Forward Transconductance	g_{FS}	$V_{\text{GS}} = 5\text{V}, I_D = 5\text{A}$	--	15	--	S
Dynamic Parameters						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 15\text{V}, f = 1.0\text{MHz}$	--	531	--	pF
Output Capacitance	C_{oss}		--	68	--	
Reverse Transfer Capacitance	C_{rss}		--	54	--	
Total Gate Charge	Q_g	$V_{\text{DD}} = 15\text{V}, I_D = 5\text{A}, V_{\text{GS}} = 10\text{V}$	--	14.8	--	nC
Gate-Source Charge	Q_{gs}		--	2.6	--	
Gate-Drain Charge	Q_{gd}		--	2.9	--	
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 15\text{V}, I_D = 5\text{A}, R_G = 3\Omega$	--	4.5	--	ns
Turn-on Rise Time	t_r		--	2.5	--	
Turn-off Delay Time	$t_{\text{d}(\text{off})}$		--	14.5	--	
Turn-off Fall Time	t_f		--	3.5	--	
Drain-Source Body Diode Characteristics						
Continuous Body Diode Current	I_S	$T_C = 25^\circ\text{C}$	--	--	6.5	A
Body Diode Voltage	V_{SD}	$T_J = 25^\circ\text{C}, I_{\text{SD}} = 5\text{A}, V_{\text{GS}} = 0\text{V}$	--	--	1.2	V
Reverse Recovery Charge	Q_{rr}	$I_F = 5\text{A}, V_{\text{GS}} = 0\text{V}$ $dI/dt = 100\text{A/us}$	--	56	--	nC
Reverse Recovery Time	T_{rr}		--	47	--	ns

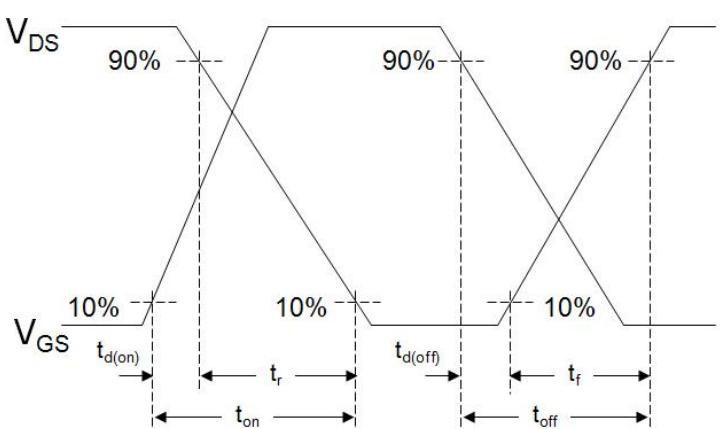
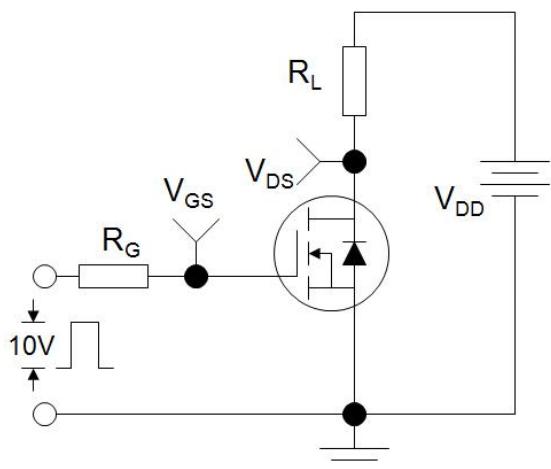
Notes

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. EAS condition : $T_J=25^\circ\text{C}$, $V_{\text{DD}}=30\text{V}$, $V_{\text{GS}}=10\text{V}$, $L=0.5\text{mH}$, $R_G=25\Omega$
3. Identical low side and high side switch with identical R_G

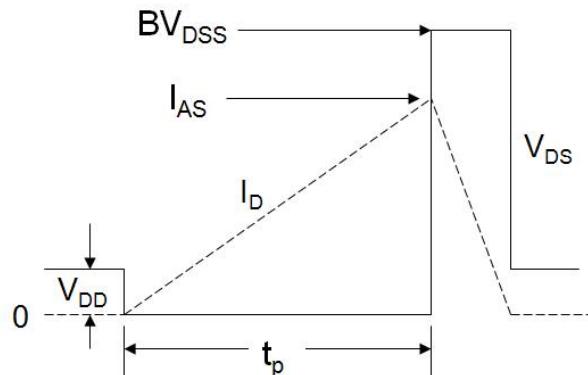
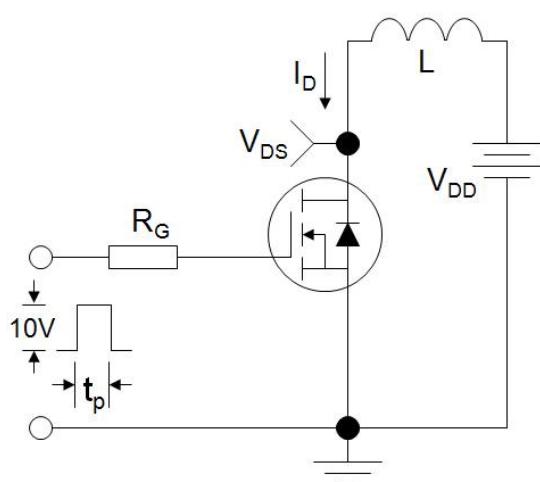
Gate Charge Test Circuit



Switch Time Test Circuit



EAS Test Circuit



NMOS Typical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted

Figure 1. Output Characteristics

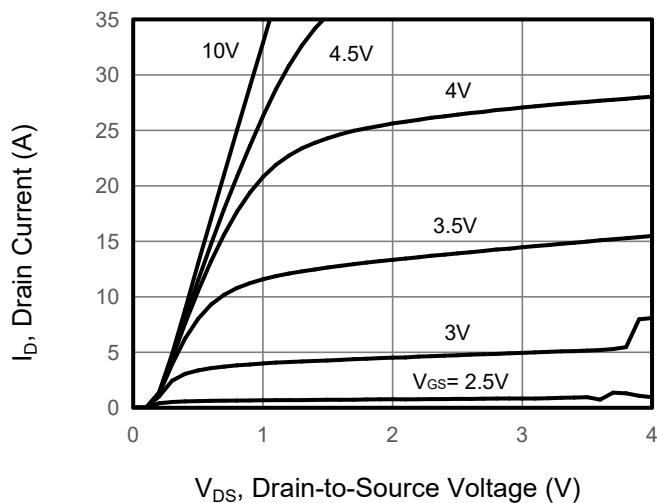


Figure 2. Transfer Characteristics

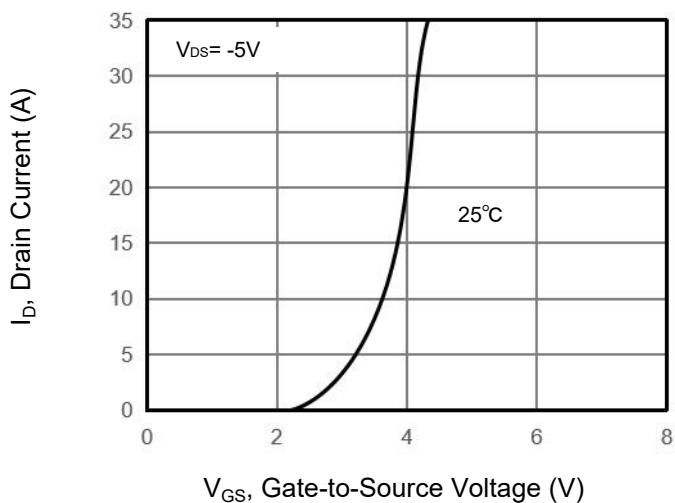


Figure 3. Drain Source On Resistance

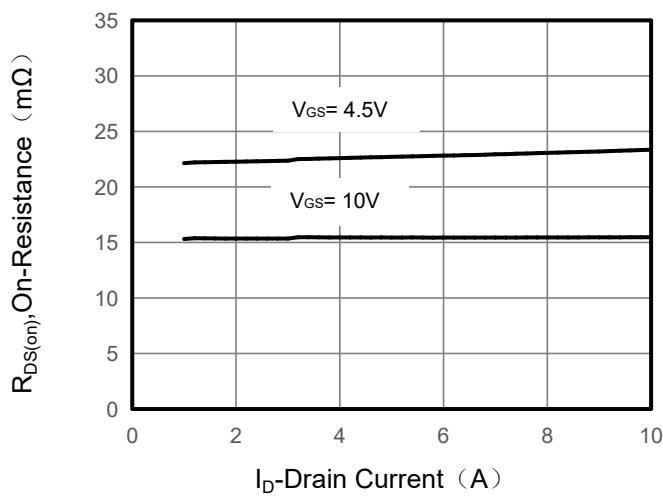


Figure 4. Gate Charge

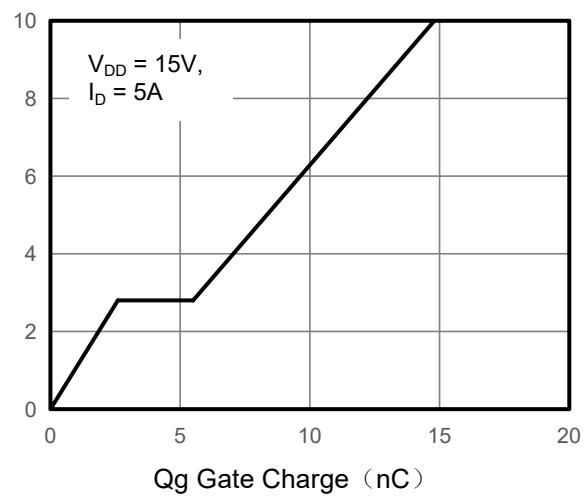


Figure 5. Capacitance

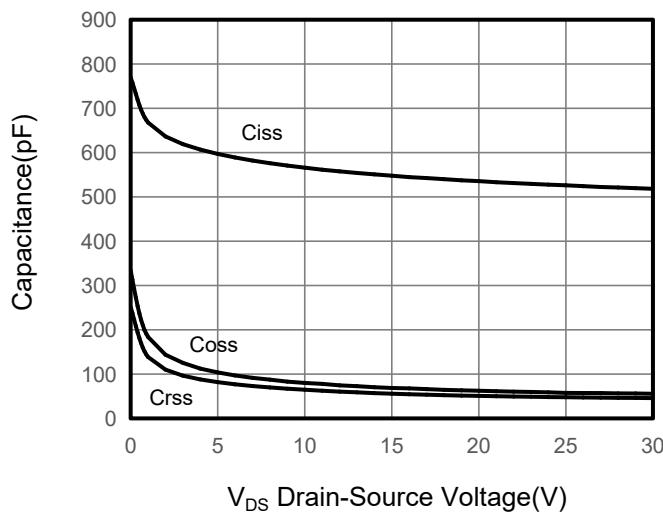
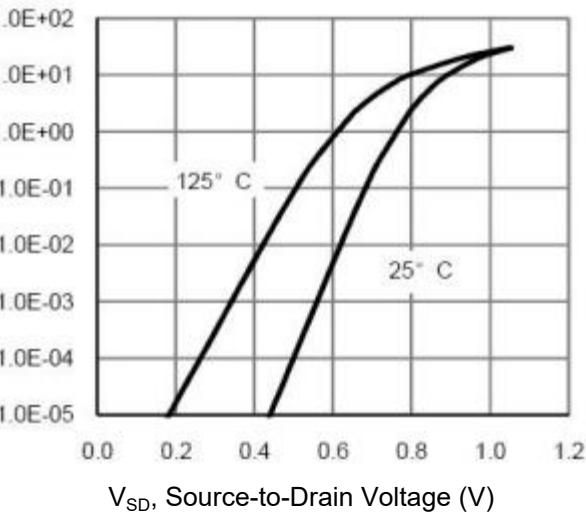


Figure 6. Source-Drain Diode Forward



NMOS Typical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted

Figure 7. Drain-Source On-Resistance

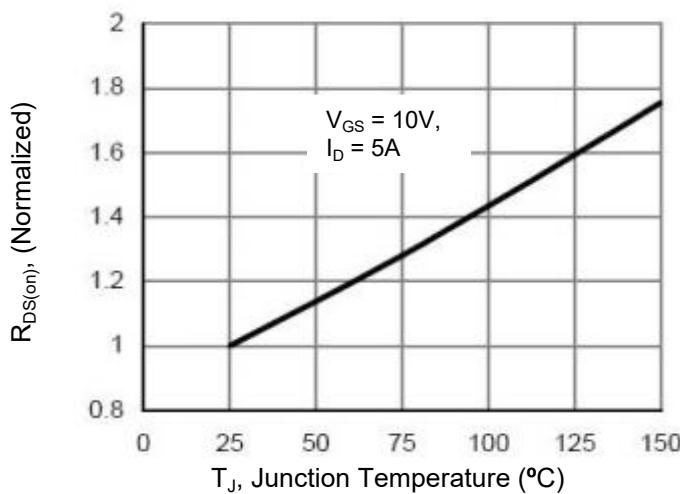


Figure 8. Safe Operation Area

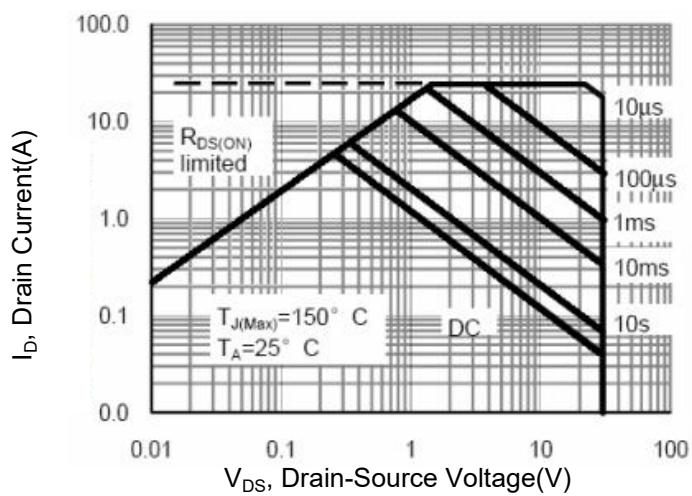
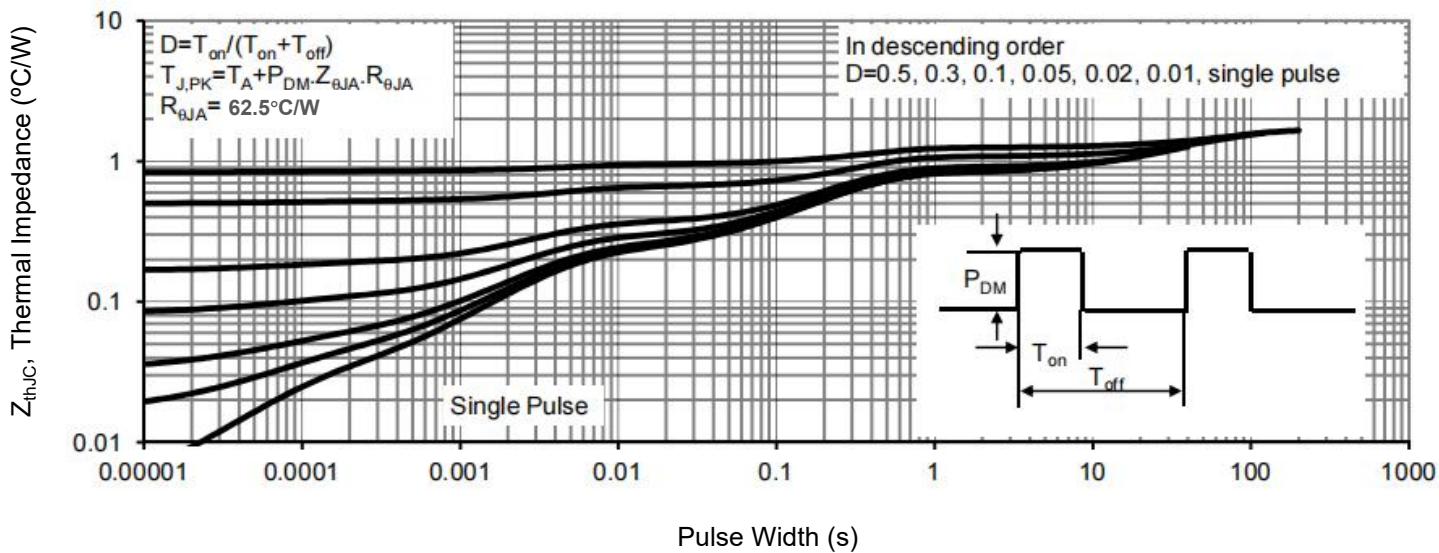


Figure 9. Normalized Maximum Transient Thermal Impedance



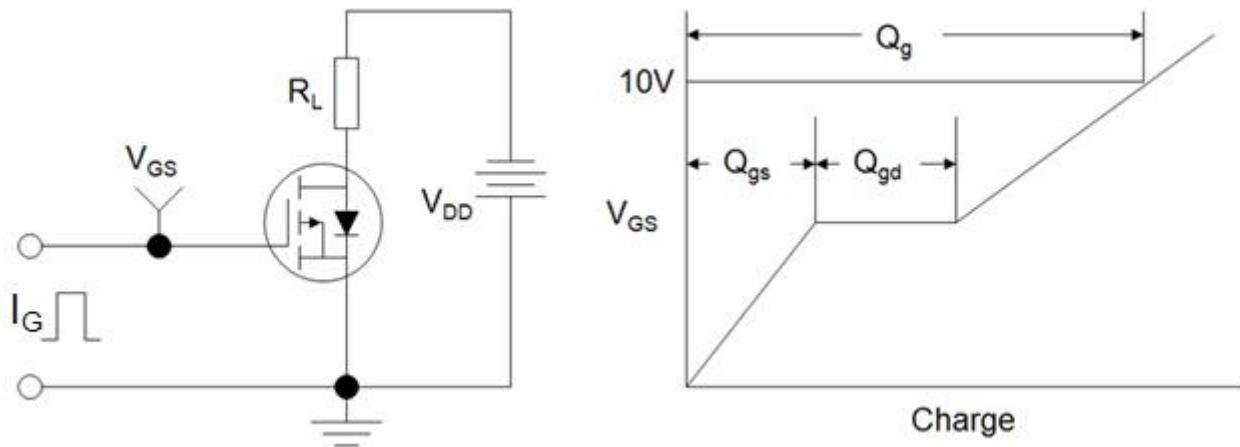
PMOS Specifications $T_J = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
Static Parameters						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-30	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = -30\text{V}, V_{\text{GS}} = 0\text{V}$	--	--	-1	μA
Gate-Source Leakage	I_{GSS}	$V_{\text{GS}} = \pm 20\text{V}$	--	--	± 100	nA
Gate-Source Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250\mu\text{A}$	-1	-1.6	-2.5	V
Drain-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = -10\text{V}, I_D = -4\text{A}$	--	35	45	$\text{m}\Omega$
		$V_{\text{GS}} = -4.5\text{V}, I_D = -4\text{A}$	--	54	70	
Forward Transconductance	g_{FS}	$V_{\text{DS}} = -5\text{V}, I_D = -5\text{A}$	--	8	--	S
Dynamic Parameters						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -15\text{V}, f = 1.0\text{MHz}$	--	563	--	pF
Output Capacitance	C_{oss}		--	77	--	
Reverse Transfer Capacitance	C_{rss}		--	67	--	
Total Gate Charge	Q_g	$V_{\text{DD}} = -15\text{V}, I_D = -4\text{A}, V_{\text{GS}} = -10\text{V}$	--	11	--	nC
Gate-Source Charge	Q_{gs}		--	2	--	
Gate-Drain Charge	Q_{gd}		--	2.6	--	
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -15\text{V}, I_D = -4\text{A}, R_G = 3\Omega$	--	7.5	--	ns
Turn-on Rise Time	t_r		--	5.5	--	
Turn-off Delay Time	$t_{\text{d}(\text{off})}$		--	19	--	
Turn-off Fall Time	t_f		--	7	--	
Drain-Source Body Diode Characteristics						
Continuous Body Diode Current	I_S	$T_C = 25^\circ\text{C}$	--	--	-5	A
Body Diode Voltage	V_{SD}	$T_J = 25^\circ\text{C}, I_{\text{SD}} = -4\text{A}, V_{\text{GS}} = 0\text{V}$	--	--	-1.2	V
Reverse Recovery Charge	Q_{rr}	$I_F = -4\text{A}, V_{\text{GS}} = 0\text{V}$ $dI/dt = -100\text{A}/\mu\text{s}$	--	66	--	nC
Reverse Recovery Time	T_{rr}		--	53	--	ns

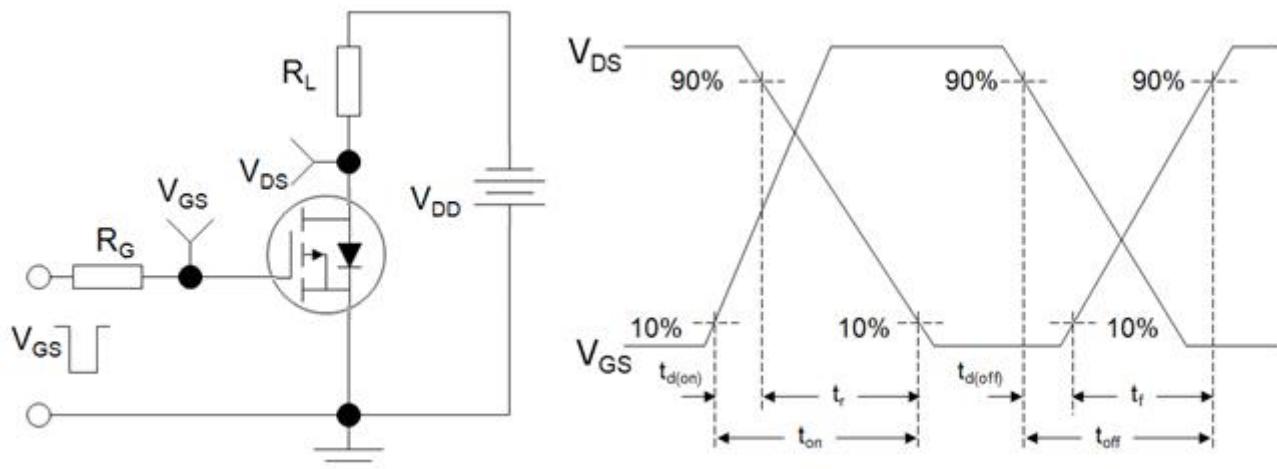
Notes

1. Repetitive Rating: Pulse width limited by maximum junction temperature
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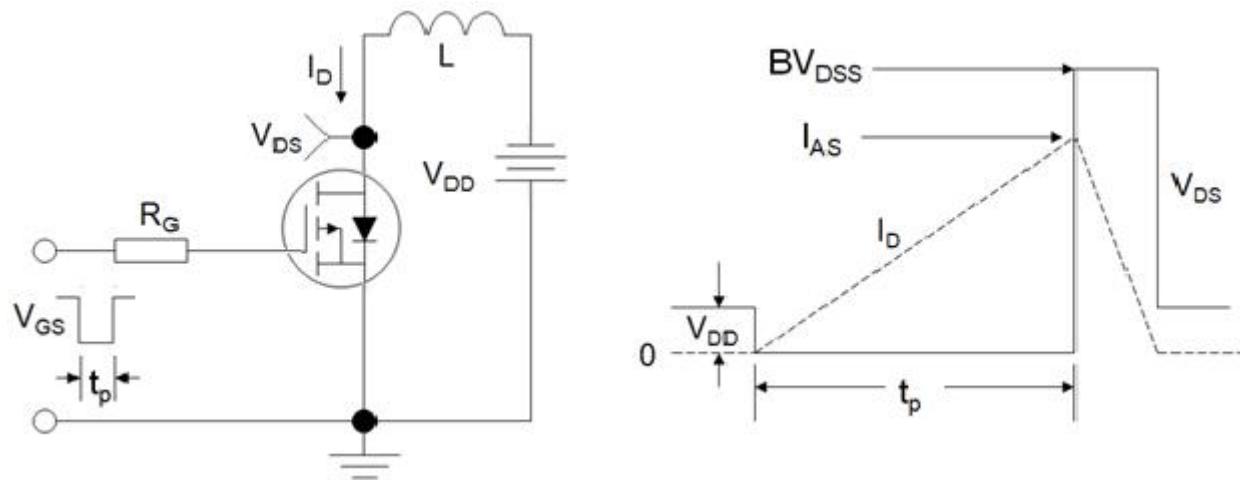
Gate Charge Test Circuit



Switch Time Test Circuit



EAS Test Circuit



PMOS Typical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted

Figure 1. Output Characteristics

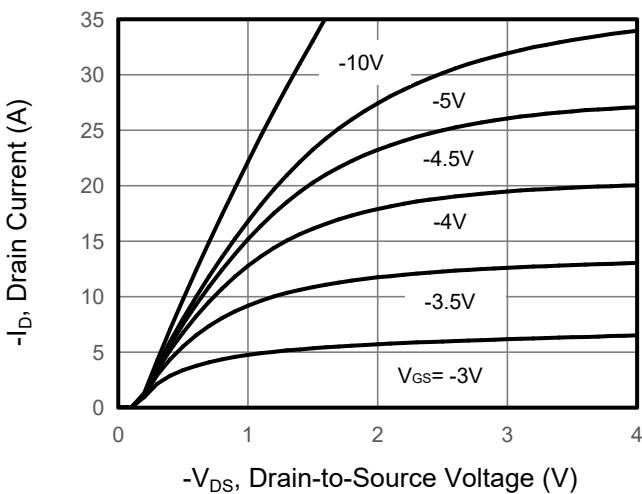


Figure 2. Transfer Characteristics

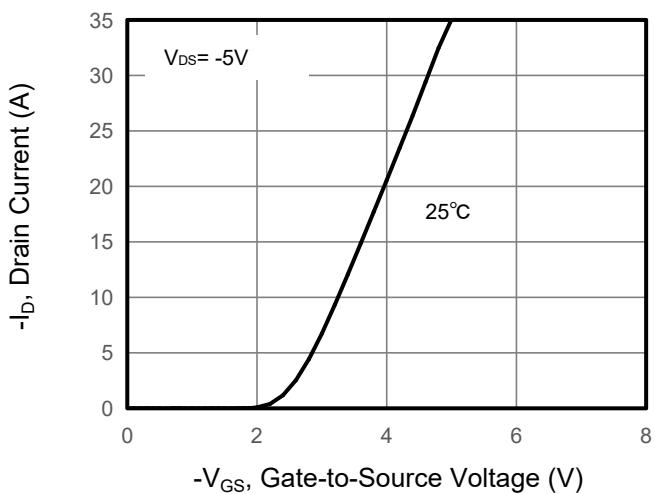


Figure 3. Drain Source On Resistance

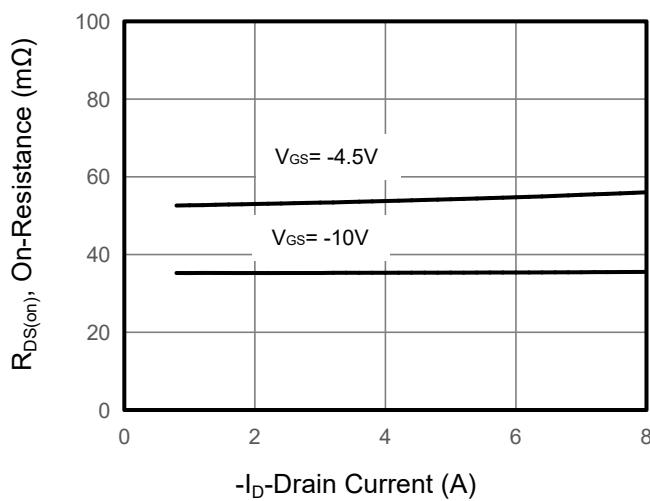


Figure 4. Gate Charge

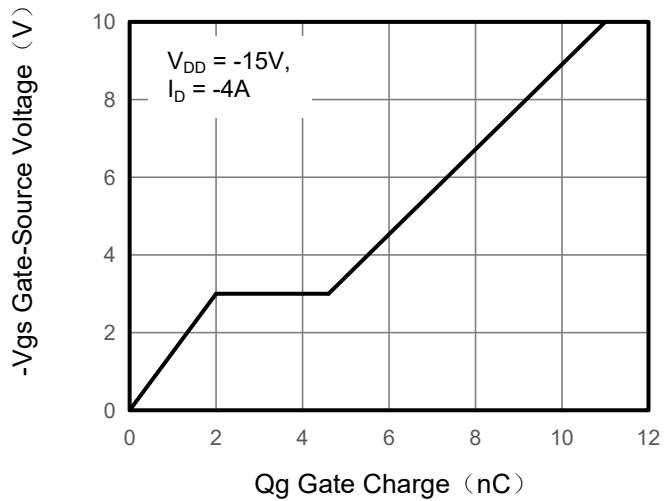


Figure 5. Capacitance

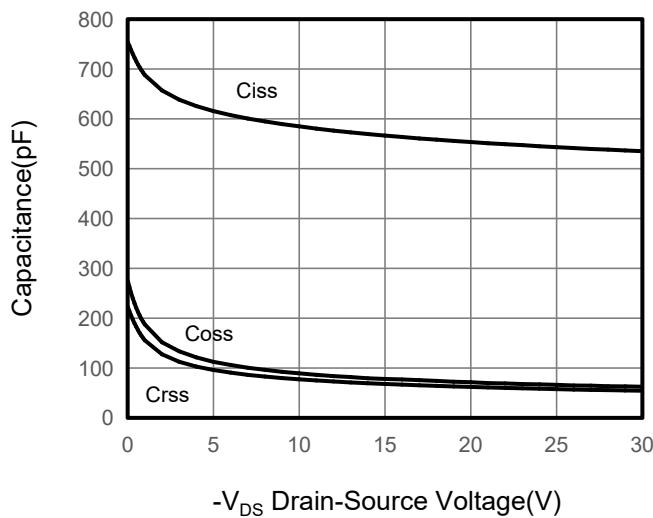
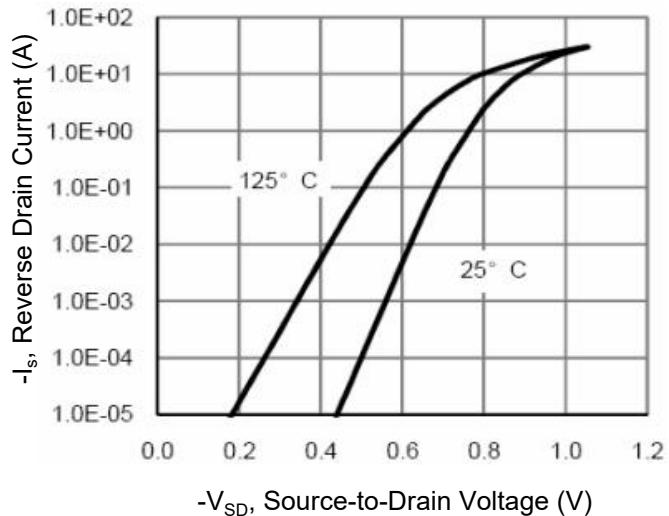


Figure 6. Source-Drain Diode Forward



PMOS Typical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted

Figure 7. Drain-Source On-Resistance

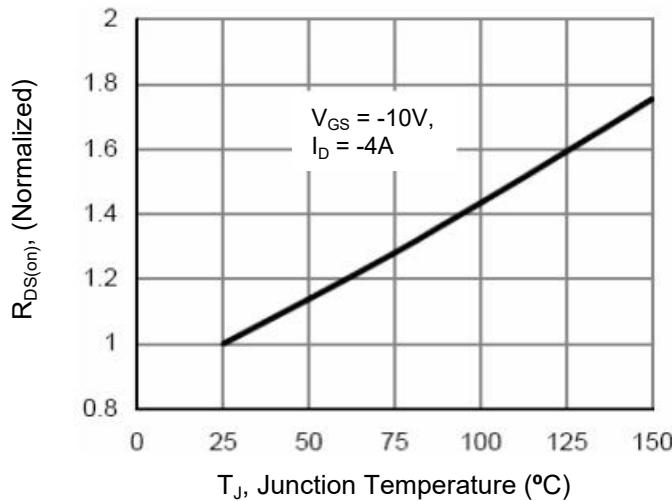


Figure 10. Safe Operation Area

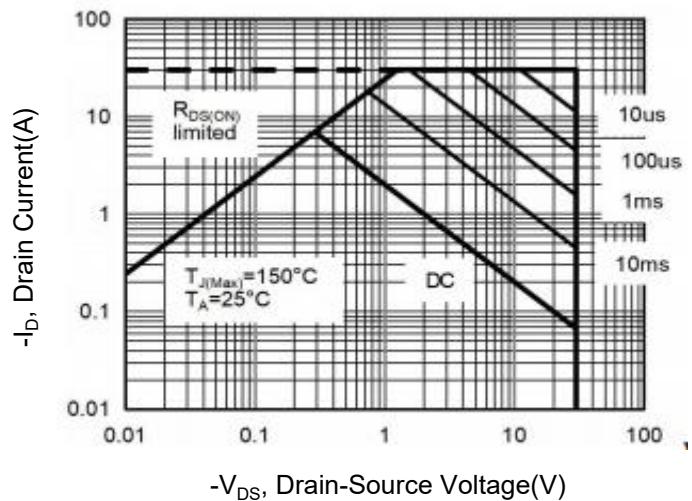
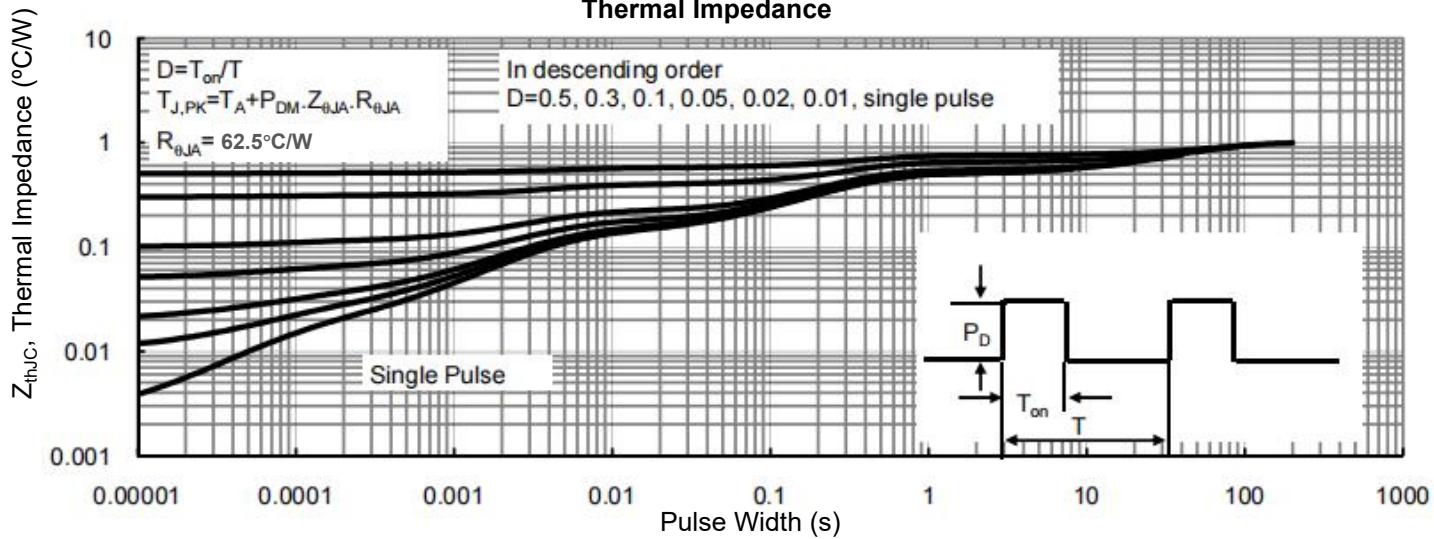
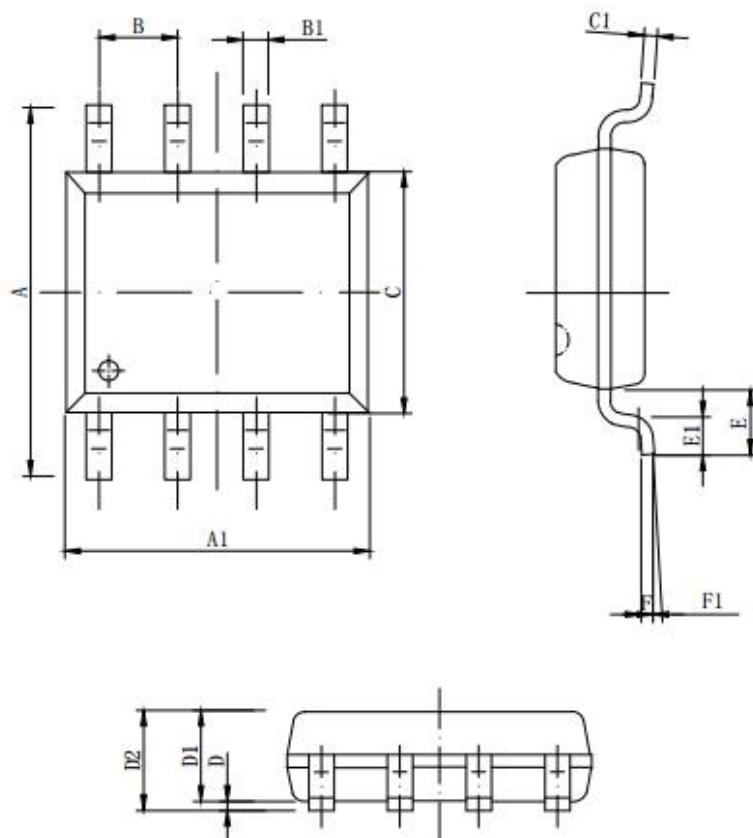


Figure 9. Normalized Maximum Transient Thermal Impedance



SOP-8 Dual Package Information

Symbol	Dimensions in Millimeters		
	MIN.	NOM.	MAX.
A	5.800	6.000	6.200
A1	4.800	4.900	5.000
B	1.270BSC		
B1	0.35^8x	0.40^8x	0.45^8x
C	3.780	3.880	3.980
C1	--	0.203	0.253
D	0.050	0.150	0.250
D1	1.350	1.450	1.550
D2	1.500	1.600	1.700
D2	1.500	1.600	1.700
E	1.060REF		
E1	0.400	0.700	0.100
F	0.250BSC		
F1	2°	4°	6°